## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10570663	ENDO ET AL.
Examiner	Art Unit
Hsien-ming Lee	2823

SEARCHED						
Subclass	Date	Examiner				

SEARCH NOTES		
Search Notes	Date	Examiner
EAST attached (USPAT, USPG, USOCR, EPO, JPO, IBM, Derwent)	3/17/08	HL

	INTERFERENCE SEA	ARCH	
Class	Subclass	Date	Examiner

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